Cylindrical cavity method to measure the complex permittivity of low-loss dielectric rods
CONTENTS

FOREWORD ........................................................................................................................... 3
1 Scope .................................................................................................................................. 5
2 Normative references ....................................................................................................... 5
3 Measurement parameters ................................................................................................. 5
4 Theory and calculation equations .................................................................................... 5
5 Measurement system ....................................................................................................... 12
6 Measurement procedure ................................................................................................. 14
  6.1 Preparation of measurement apparatus ..................................................................... 14
  6.2 Measurement of reference level .............................................................................. 14
  6.3 Measurement of cavity parameters: $\sigma_r$ ............................................................. 14
  6.4 Measurement of complex permittivity of test sample: $\varepsilon'$, $\tan \delta$ ................ 15
Annex A (informative) Example of measurement results and accuracy ............................. 16
  A.1 Measurement of $\varepsilon'$ and $\tan \delta$ values ...................................................... 16
  A.2 Measurement uncertainty of $\varepsilon'$ and $\tan \delta$ .............................................. 17

Bibliography .......................................................................................................................... 19

Figure 1 – Structure of a cylindrical cavity resonator ............................................................ 6
Figure 2 – Correction factor $C_1$ for $\varepsilon'$ .................................................................. 7
Figure 3 – Correction factor $C_2$ for $\tan \delta$ with the different values of $d_1$ ............... 9
Figure 4 – Schematic diagram of measurement systems .................................................... 13
Figure 5 – Resonance frequency $f_0$, insertion attenuation $IA_0$ and half-power band width $f_{\text{BW}}$ ................................................................. 14
Figure 6 – Frequency responses of the TM$_{010}$ mode of cylindrical cavity ................... 15

Table 1 – Numerical values of correction factor $C_1$ ....................................................... 8
Table 2 – Numerical values of correction factor $C_2$ ....................................................... 10
Table 3 – Numerical values of correction factor $C_2$ ....................................................... 11
Table A.1 – The parameters of the cavity and the rod sample .......................................... 16
Table A.2 – The resonant frequencies and unloaded $Q$-factors ...................................... 16
Table A.3 – The approximate values and the relative conductivity value ......................... 16
Table A.4 – Correction factors and the measurement results ........................................... 16
Table A.5 – The measurement uncertainty of $\varepsilon'$ ..................................................... 17
Table A.6 – The measurement uncertainty of $\tan \delta$ ..................................................... 18
INTERNATIONAL ELECTROTECHNICAL COMMISSION

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CYLINDRICAL CAVITY METHOD TO MEASURE
THE COMPLEX PERMITTIVITY OF LOW-LOSS DIELECTRIC RODS

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The text of this standard is based on the following documents:

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1 Scope

This International Standard relates to a measurement method for complex permittivity of a dielectric rod at microwave frequency. This method has been developed to evaluate the dielectric properties of low-loss materials in coaxial cables and electronic devices used in microwave systems. It uses the TM010 mode in a circular cylindrical cavity and presents accurate measurement results of a dielectric rod sample, where the effect of sample insertion holes is taken into account accurately on the basis of the rigorous electromagnetic analysis.

In comparison with the conventional method described in IEC 60556 [2], this method has the following characteristics:

- the values of the relative permittivity $\varepsilon'$ and loss tangent $\tan\delta$ of a dielectric rod sample can be measured accurately and non-destructively;
- the measurement accuracy is within 1,0 % for $\varepsilon'$ and within 20 % for $\tan\delta$;
- the effect of sample insertion holes is corrected using correction charts presented;
- this method is applicable for the measurements on the following condition:
  - frequency: $1 \text{ GHz} \leq f \leq 10 \text{ GHz}$;
  - relative permittivity: $1 \leq \varepsilon'\leq 100$;
  - loss tangent: $10^{-4} \leq \tan\delta \leq 10^{-1}$.

2 Normative references

Void.

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1 Figures in square brackets refer to the Bibliography.